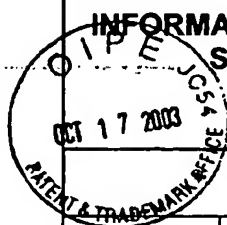


**INFORMATION DISCLOSURE
STATEMENT**

 Atty Docket:
 Serial No.:
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 02GR2182(54480)
 10/672,931
 POIROUX ET AL.
 SEPTEMBER 26, 2003

U.S. PATENT DOCUMENTS

Examiner Initials		Document Number	Date	Name	Class	Sub Class	Filing Date
	AA						
	AB						
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	AD						
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	AG						
	AH						
	AI						

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Sub Class	Translation
	AJ						
	AK						

OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)

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EXAMINER:

DATE CONSIDERED:

3/9/04

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.